

TECHNICAL REPORT



Damp heat, steady state (unsaturated pressurized vapour with air)
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IEC TR 63141:2020

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CONTENTS

FOREWORD.....	5
INTRODUCTION.....	7
1 Scope.....	8
2 Normative references	8
3 Terms and definitions	8
4 Overview of HAST and air-HAST	9
4.1 Overview of HAST chamber	9
4.1.1 Structure of HAST chamber	9
4.1.2 Definition of humidity	10
4.2 Structure of air-HAST equipment	12
4.2.1 General	12
4.2.2 Air concentration and relative humidity	14
5 Evaluation of tin whisker growth from lead-free plating and solder-joints.....	14
5.1 Whisker of lead-free solder (comb-type substrate)	14
5.1.1 General	14
5.1.2 Summary of evaluation results of solder-joint whisker growth [3] [4]	15
5.1.3 Conclusion	24
5.2 Lead-free whisker of plating (mounting substrate).....	25
5.2.1 General	25
5.2.2 Test method	25
5.2.3 Test results.....	26
5.2.4 Observations	27
5.2.5 Conclusion	29
6 Applied case of JISSO using electrically-conductive adhesive and acceleration test under humidity environments for joining parts	29
6.1 General.....	30
6.2 Experiment method	30
6.2.1 Testing material.....	30
6.2.2 Test conditions	30
6.2.3 Measurement and evaluation method	31
6.3 Test results	31
6.3.1 Experimental result.....	31
6.3.2 Test result (1608R/paste A).....	36
6.4 Points of attention.....	38
6.5 Summary	38
7 Applied air-HAST to c-Si PV modules evaluation tests	39
7.1 Background and objective	39
7.2 Photovoltaic module structure and deterioration factors	39
7.3 Test methods	40
7.3.1 Crystalline silicon photovoltaic module type-approval international standard	40
7.3.2 Air-HAST work.....	41
7.3.3 Test samples	41
7.3.4 Test conditions	42
7.3.5 Measurement and analysis	44
7.4 Test results	44
7.4.1 DHT testing	44

7.4.2	Saturated HAST.....	46
7.4.3	Air-HAST	47
7.4.4	External appearance comparison.....	48
7.4.5	Use of dark I-V measurement to infer deterioration factors	50
7.4.6	Use of ion chromatography to quantify residual acetic acid ions	50
7.5	Discussion	51
7.5.1	Environment test method comparisons	51
7.5.2	Power-loss profiles by moisture permeation.....	52
7.5.3	Comparisons by ion chromatography acetic acid quantification.....	52
7.6	Conclusion.....	53
8	Summary	54
	Bibliography.....	55
	Figure 1 – Two types of HAST equipment and their structures	9
	Figure 2 – Image of air vent process	11
	Figure 3 – Saturated test	11
	Figure 4 – Unsaturated test.....	12
	Figure 5 – Structure of two-vessel type air-HAST chamber	13
	Figure 6 – Structure of one-vessel type air-HAST chamber.....	14
	Figure 7 – Example of test vehicle with comb pattern.....	15
	Figure 8 – Process flow for sample build.....	16
	Figure 9 – Temperature/relative humidity profiles of HAST and air-HAST.....	17
	Figure 10 – Whisker generation situation in air-HAST.....	19
	Figure 11 – Mapping of the cross-section at the solder fillet in HAST.....	20
	Figure 12 – Mapping of the cross-section at the solder fillet in air-HAST	20
	Figure 13 – Arrhenius plot of the bromine-based flux	22
	Figure 14 – Reciprocal of relative humidity of whisker generation on solder.....	22
	Figure 15 – Humidity properties of whisker generation on solder (pt.2)	23
	Figure 16 – Evaluated sample.....	25
	Figure 17 – Whisker formation (Substrate: Cu)	27
	Figure 18 – Cross-section inspection results with electron-imaging (Substrate: Cu)	28
	Figure 19 – Elements analysis	29
	Figure 20 – Substrate for conductive resistance measurement and example of component mounting.....	30
	Figure 21 – Humidity test conductive resistance monitor test status.....	31
	Figure 22 – Example of the conductive resistance value change	32
	Figure 23 – Weibull plot of temperature acceleration (under fixed humidity conditions)	32
	Figure 24 – Arrhenius plot (fixed humidity).....	33
	Figure 25 – Weibull plot of humidity acceleration (under fixed temperature conditions)	34
	Figure 26 – Arrhenius plot (fixed temperature)	35
	Figure 27 – Eyring plot of all conditions	35
	Figure 28 – Comparison of paste (120 °C/85 % RH Air-HAST).....	36
	Figure 29 – Cross-section analysis of 1608R after a humidity test (SEM image)	37
	Figure 30 – Magnified image of cross-section analysis of 1608R after a humidity test (SEM image).....	37

Figure 31 – Cross-section analysis of 1608R after a humidity test (SEM image) and examples of componential analysis by EDX	38
Figure 32 – Structure of c-Si PV module	40
Figure 33 – Qualification test sequence in IEC 61215-1 [23]	41
Figure 34 – Appearance of modules	42
Figure 35 – EL images after DHT	45
Figure 36 – Degradation profiles with DHT	46
Figure 37 – EL images of HAST 105 °C/100 % RH	46
Figure 38 – EL images after HAST 120 °C/100 % RH	47
Figure 39 – Degradation profiles with HAST	47
Figure 40 – EL images after air-HAST	48
Figure 41 – Degradation profiles with air-HAST	48
Figure 42 – Appearance of modules after each test	49
Figure 43 – Dark I-V	50
Figure 44 – Residue of acetate ion and retention of P_{max} after each test	51
Table 1 – Test conditions	15
Table 2 – Influence of fluxes and circumstances to whisker growth	18
Table 3 – Whisker generation in HAST	18
Table 4 – Whisker generation in air-HAST	19
Table 5 – Comparison of coefficients for Equations (5), (6) and (7)	24
Table 6 – Details of evaluated samples	26
Table 7 – Lead frames composition	26
Table 8 – Environmental test conditions	26
Table 9 – Electrically-conductive adhesives	30
Table 10 – Testing material	31
Table 11 – Test conditions	36
Table 12 – Example of failure modes of PV module via materials	40
Table 13 – Specifications of materials used in PV module	42
Table 14 – Test conditions	43
Table 15 – Test conditions and partial pressures	43

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**DAMP HEAT, STEADY STATE
(UNSATURATED PRESSURIZED VAPOUR WITH AIR)**

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IEC TR 63141, which is a Technical Report, has been prepared by IEC technical committee 104: Environmental conditions, classification and methods of test.

The text of this Technical Report is based on the following documents:

Draft TR	Report on voting
104/834/DTR	104/853A/RVDTR

Full information on the voting for the approval of this Technical Report can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

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INTRODUCTION

Highly accelerated stress test (HAST), is a high temperature (100 °C or more), high humidity steady test of unsaturated pressurized steam of 85 % RH, and is the original test method that was developed for the evaluation of corrosion of packaged semiconductor wiring. This test method, often referred to as HAST, is applied to primarily non-hermetically sealed small electronic components, and has been standardized as a standard test method for evaluating, in an accelerated manner, the resistance to the deteriorative effect of high temperature and high humidity (IEC 60068-2-66). The equipment used for this test method is a chamber, filled with unsaturated water vapour, called a HAST chamber.

However, in life evaluation test conditions, acceleration cannot be obtained without air from the environment being incorporated into the HAST chamber. This test method is referred to as air-HAST.

Examples of the application of air-HAST are whiskers evaluation of lead-free solder, deterioration life evaluation of conductive paste, and deterioration life evaluation of solar cells and are given in this document in order to provide an understanding of air-HAST with the aim, in future, to standardize air-HAST.

The International Electrotechnical Commission (IEC) draws attention to the fact that it is claimed that compliance with this document may involve the use of a patent concerning whisker evaluation given in Clause 5.

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DAMP HEAT, STEADY STATE (UNSATURATED PRESSURIZED VAPOUR WITH AIR)

1 Scope

This document describes a new test method to control the volume of air injected into a conventional HAST chamber filled with water vapour. This document provides an overview of the conventional HAST chamber, an overview of the air-HAST equipment where air is incorporated into the HAST chamber, an example of an air-HAST test apparatus, and application examples of air-HAST.

2 Normative references

There are no normative references in this document.

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

3.1

galvanic corrosion

corrosion damage induced when two dissimilar materials are coupled in a corrosive electrolyte

3.2

Kirkendall effect

motion of the boundary layer between two metals that occurs as a consequence of the difference in diffusion rates of the metal atoms

3.3

whisker

metallic protrusion which grows up naturally during storage or in use

3.4

HAST

highly accelerated stress test

original test method developed to evaluate the corrosion of the semiconductor wiring at a high temperature of 100 °C or more

3.5

air-HAST

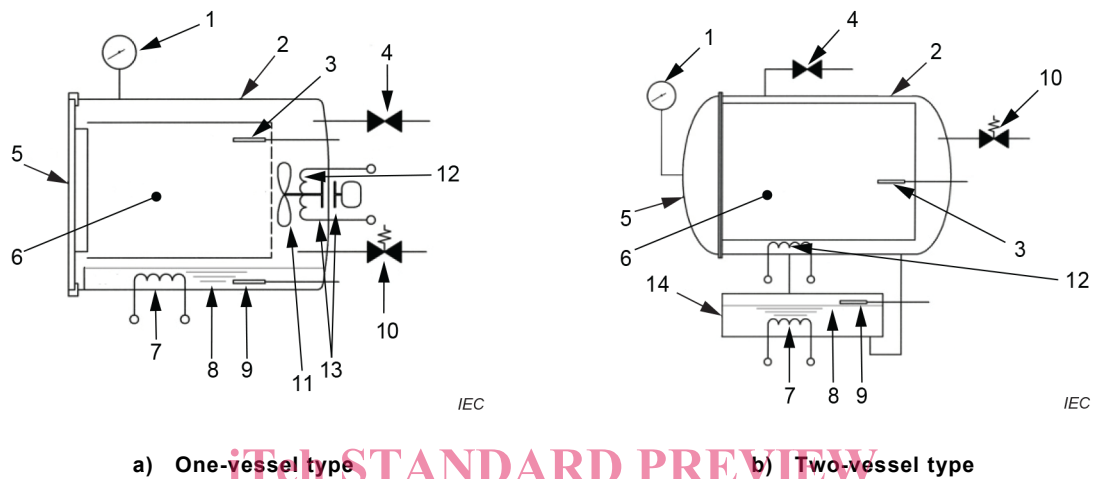
HAST test method with the addition of further air partial pressure in a HAST chamber

4 Overview of HAST and air-HAST

4.1 Overview of HAST chamber

4.1.1 Structure of HAST chamber

HAST is an evaluation test at a high-temperature and high-humidity unsaturated pressurized steam atmosphere environment of more than 100 °C. The test apparatus is roughly divided into a one-vessel type and a two-vessel type, as shown in Figure 1.



a) One-vessel type

b) Two-vessel type

Key

- | | |
|----|--|
| 1 | pressure gauge |
| 2 | pressure vessel |
| 2 | temperature sensor for moisture |
| 4 | safety valve |
| 5 | door |
| 6 | working space |
| 7 | heater for humidifying water |
| 8 | humidifying water |
| 9 | temperature sensor for humidifying water |
| 10 | air-exhaust valve |
| 11 | fan |
| 12 | heater for moisture fan for air |
| 13 | magnetic coupling |
| 14 | pressure vessel 2 |

Figure 1 – Two types of HAST equipment and their structures

The configuration of the one-vessel type and the configuration of the two-vessel type are explained as follows.

a) Configuration of the one-vessel type (See Figure 1 a))

This type of chamber is called a one-vessel type because it has only one pressure vessel. The inner cylinder provided inside the pressure vessel is divided into a steam generator for supplying humidifying water vapour and a working space to set the sample. A fan for generating a flow of steam from the steam generator to the working space is provided in the back of the inner cylinder. Heaters are arranged outside of this fan and in the steam generator. Steam flow rate of this system is suppressed to about the flow rate of natural convection.

b) Configuration of the two-vessel type (See Figure 1 b))

This type of chamber is called a two-vessel type because it is composed of two different pressure vessels: the test chamber which sets the sample and the steam generation chamber which supplies humidifying water vapour. Heaters are respectively located in the test chamber and the steam generation chamber. Water vapour is fed by boiling water vapour pressure to the test chamber from the steam generation chamber holding the humidifying water, the amount that was the condensed water goes back into the steam generation chamber. There is an inner cylinder in the test chamber, and a heater is provided on the outside of this inner cylinder. Heat from the heater is transmitted to the inner cylinder, keeping the temperature of the entire working space at a constant level. This system is also referred to as a natural convection because it does not require a fan for the circulation of water vapour.

4.1.2 Definition of humidity

HAST is carried out in a closed vessel which is isolated from the atmosphere of the atmospheric pressure (pressure vessel), under the assumption that air is absent from the filled water vapour atmosphere. Therefore during the start of HAST, steps to eliminate air (Figure 2 air vent process) are always taken. The humidifying water is heated and boiled by the heater, the exhaust valve is opened and the test vessel is filled with 100 % water vapour until all air is discharged. Then the exhaust valve is closed to perform heating until the test temperature in the vessel is reached again. The difference between the saturated test and unsaturated test in the working space in the chamber is then recorded. The state of the saturated test is shown in Figure 3. The state of the unsaturated test is shown in Figure 4. The air vent process is executed in both the saturated test and unsaturated test, the chamber needs to be filled with 100 % water vapour without air.

In saturation conditions, the working space is kept at a constant temperature by water vapour generated from the humidifying water because the heating source is only humidifying the water heater.

T_1 : is the humidification water temperature;

T_2 : is the test space temperature.

In this case the vessel temperature is $T_1 = T_2$.

In the case of the unsaturated test, a heater for heating the working space is installed in the chamber. In the apparatus, water vapour generated from the humidifying water enters the working space, it is re-heated by the heater to a higher temperature than the water vapour in the surroundings. When the temperature in the vessel is controlled to $T_1 < T_2$, the working space is an unsaturated vapour atmosphere. At this stage, the relative humidity (RH) of the working space is determined by the following equation:

$$H = P_1 / P_2 \times 100$$

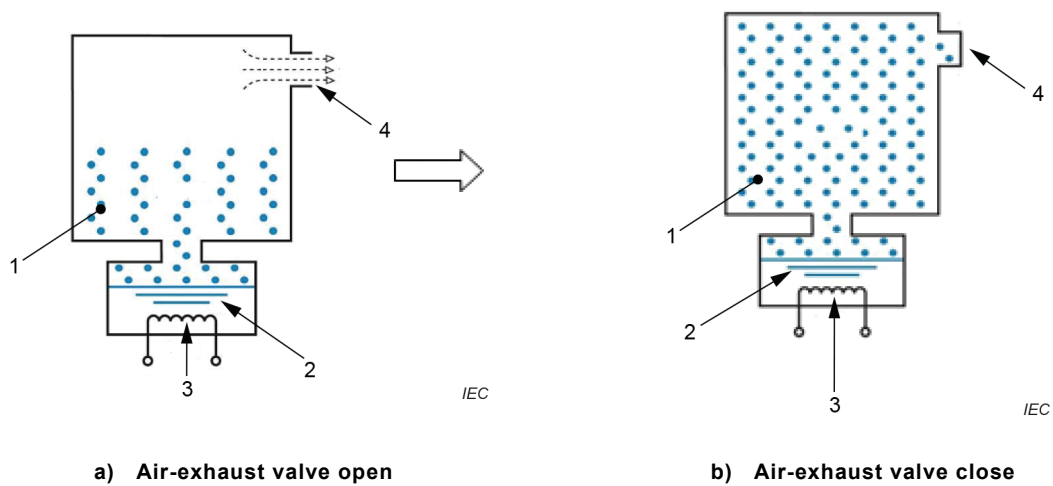
where

H : is the relative humidity, RH (%);

P_1 : is the saturated water vapour pressure in the humidification water temperature T_1 (MPa);

P_2 : is the saturated water vapour pressure in the test space temperature T_2 (MPa).

At this stage the vessel pressure, P_1 , is the test pressure because it is determined by the temperature of the humidification water (T_1).



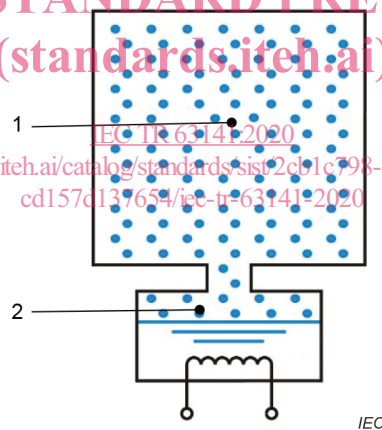
Key

- 1 water vapour
- 2 humidifying water
- 3 heater
- 4 air-exhaust valve

Figure 2 – Image of air vent process

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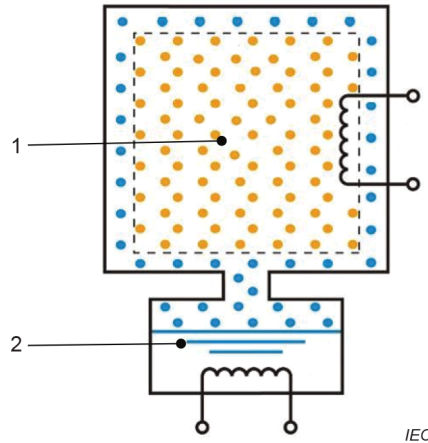
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Key

- 1 working space
- 2 humidifying water

Figure 3 – Saturated test



Key

- 1 working space
- 2 humidifying water

Figure 4 – Unsaturated test

4.2 Structure of air-HAST equipment

4.2.1 General

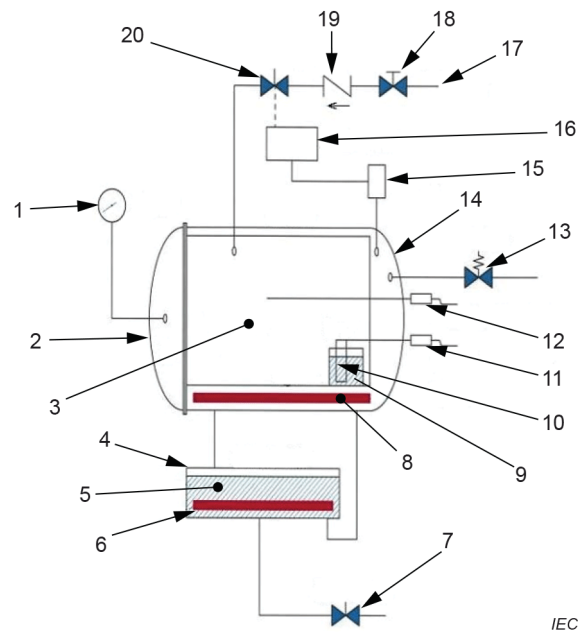
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In the case of air-HAST, it is necessary to leave the air into a traditional HAST chamber. Considering the possibility that a residual air volume greatly affects test results, it becomes necessary to accurately control the amount of air. Using a conventional HAST chamber, to ensure the air-HAST environment contains air, the following two methods are used:

- a) keeping a certain amount of air during start-up, and
- b) injecting a predetermined amount of air after discharging air to the outside of the chamber.

Technically, either method is possible. Method a) can be realized simply by omitting the vent process, but it is difficult to control the amount of air to be discharged when adjusting the air volume. Method b) injects air after discharging air, so that the entire process becomes complicated but the control of the amount of air is easy. A dual-vessel type air-HAST chamber is shown in Figure 5. This equipment, which is a wet bulb installed and provided with a pan and wick temperature sensor in the working space of a conventional two-vessel type chamber, has become a mechanism for controlling the humidification water heater (steam generator) at the specified temperature. This air-HAST system is easily obtained from a dual-vessel type HAST equipment and has the advantage of facilitating experimentation. The method consists in injecting a predetermined amount of air from the air pressure port after the system has reached a steady state and all air in the chamber has been evacuated. The air remaining in the chamber is controlled by a pressure controller, so the constant partial pressure can be held.

**Key**

1 pressure gauge	2 door	3 working space
4 pressure vessel 2	5 humidifying water	6 heater for humidifying water
7 solenoid valve for drain	8 heater for water vapour	9 wet bulb pan
10 cloth wick	11 sensor for humidifying water	12 sensor for water vapour
13 safety valve	14 pressure vessel 1	15 pressure sensor
16 pressure regulator	17 inlet	18 flow controller
19 check valve	20 solenoid valve	

Figure 5 – Structure of two-vessel type air-HAST chamber

A one-vessel air-HAST chamber (Figure 6) is used for whiskers, electrically-conducting adhesives and photovoltaic modules reliability tests. A one-vessel air-HAST chamber is of a less complex constitution providing reproducible and compatible test results. At first, the specimen is set in the vessel at room temperature, the door is closed, the test is started to create heat and humidity. This way there is no pressure damage by a sudden change in pressure and no condensation on the specimen. In addition, a forced steam of water-vapour is normally generated by means of a fan installed in the chamber to create air velocity and accurately detect humidity by a dry and wet bulb.